

**Notice of References Cited**

Application/Control No.

10/757,597

Applicant(s)/Patent Under  
Reexamination  
NISHIO ET AL.

Examiner

HELEN SHIBRU

Art Unit

2621

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0008175	01-2006	Tanaka et al.	382/276
*	B	US-2002/0090196	07-2002	Wurzer, Siegfried	386/46
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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**NON-PATENT DOCUMENTS**

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